

Notic of References Cited	Application/Control No. 10/677,043	Applicant(s)/Patent Under Reexamination THURUTHIYIL ET AL.	
	Examiner Caridad M. Everhart	Art Unit 2825	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,166,354	12-2000	Hause et al.	219/390
	B	US-5,769,540	06-1998	Schietinger et al.	374/127
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	R.J. Schreutelkamp, et al. "In situ emissivity measurements to probe the phase transformations during rapid thermal processing in Co. silicidation" Appl. Phys. Lett. Vol. 61, INo. 19, pp 2296-2298 (9 Nov. 1992).
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.